METHOD OF DEFECT ROOT CAUSE ANALYSIS

Appl. No. : 10/708,943 Confirmation No. 2942

Applicant : Long-Hui Lin Filed : April 2, 2004

TC/A.U. : 2857

Examiner : GUTIERREZ, ANTHONY

Docket No. : LKSP0028USA

Customer No. : 27765

Commissioner for Patents

P.O. Box 1450

Alexandria VA 22313-1450

AMENDMENT

Sir:

In response to the Office action of February 26, 2008, please amend the above-identified application as follows:

Remarks/Arguments begin on page 2 of this paper.